

Notice of References Cited	Application/Control No. 09/776,040		Applicant(s)/Patent Under Reexamination EHRHARDT ET AL.	
	Examiner LINH K. PHAM		Art Unit 2174	Page 1 of 1

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	X	Yang et al.; A New Evaluation Model for Security Protocols; JOURNAL OF COMMUNICATIONS, VOL. 6, NO. 6, SEPTEMBER 2011; 10 pages

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.